

## TRENCHSTOP™ IGBT4 Low Power Chip

### Features:

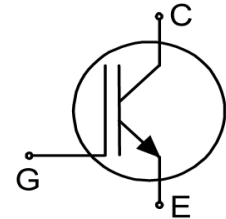
- 1200V trench & field stop technology
- Low switching losses
- Positive temperature coefficient
- Easy paralleling

### Recommended for:

- Low / medium power modules

### Applications:

- Low / medium power drives



Chip Type	V <sub>CE</sub>	I <sub>Cn</sub> <sup>1</sup>	Die Size	Package
IGC11T120T8L	1200V	8A	3.48mm x 3.19mm	Sawn on foil

### Mechanical Parameters

Die size	3.48 x 3.19		mm <sup>2</sup>
Emitter pad size	See chip drawing		
Gate pad size	0.608 x 0.608		
Area total	11.1		
Thickness	115		µm
Wafer size	200		mm
Maximum possible chips per wafer	2408		
Passivation frontside	Photoimide		
Pad metal	3200nm AlSiCu		
Backside metal	Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process		
Die bond	Electrically conductive epoxy glue and soft solder		
Wire bond	Al, ≤500µm		
Reject ink dot size	Ø 0.65mm; max. 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 25°C, <6 months	
	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen or inert gas, humidity <25%RH, temperature 17°C – 25°C, <6 months	

<sup>1</sup> Nominal collector current at TC = 100°C assuming chip assembly in TO-247 package.

## Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage, $T_{vj}=25^{\circ}\text{C}$	$V_{CE}$	1200	V
DC collector current, limited by $T_{vj\text{ max}}^2$	$I_C$	-	A
Pulsed collector current, $t_p$ limited by $T_{vj\text{ max}}^3$	$I_{C,puls}$	24	A
Gate-emitter voltage	$V_{GE}$	$\pm 20$	V
Operating junction temperature	$T_{vj}$	-40 ... +175	$^{\circ}\text{C}$
Short circuit data <sup>3/4</sup> $V_{GE}=15\text{V}$ , $V_{CC}=800\text{V}$ , $T_{vj}=150^{\circ}\text{C}$	$t_{sc}$	10	$\mu\text{s}$

## Static Characteristics (tested on wafer), $T_{vj}=25^{\circ}\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0\text{V}$ , $I_C=0.5\text{mA}$	1200	-	-	V
Collector-emitter saturation voltage	$V_{CEsat}$	$V_{GE}=15\text{V}$ , $I_C=8\text{A}$	1.58	1.85	2.07	
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=0.15\text{mA}$ , $V_{GE}=V_{CE}$	5.3	5.8	6.3	
Zero gate voltage collector current	$I_{CES}$	$V_{CE}=1200\text{V}$ , $V_{GE}=0\text{V}$	-	-	1	$\mu\text{A}$
Gate-emitter leakage current	$I_{GES}$	$V_{CE}=0\text{V}$ , $V_{GE}=20\text{V}$	-	-	120	nA
Integrated gate resistor	$r_G$		none			$\Omega$

## Electrical Characteristics <sup>3</sup>

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter saturation voltage	$V_{CEsat}$	$V_{GE}=15\text{V}$ , $I_C=8\text{A}$ , $T_{vj}=150^{\circ}\text{C}$	-	2.25	-	V
Input capacitance	$C_{ies}$	$V_{CE}=25\text{V}$ , $V_{GE}=0\text{V}$ , $f=1\text{MHz}$ $T_{vj}=25^{\circ}\text{C}$	-	490	-	pF
Reverse transfer capacitance	$C_{res}$		-	30	-	

<sup>2</sup> Depending on thermal properties of assembly.

<sup>3</sup> Not subject to production test - verified by design/characterization.

<sup>4</sup> Allowed number of short circuits: <1000; time between short circuits: >1s.